

Headquarter:

Via Cadriano, 23 - 40057 Granarolo dell'Emilia (BO)

Laboratory:

Via Fabio Filzi, 68 - 20032 Cormano (MI)

LAB N° 0001 L

TEST REPORT

Number:

L0012337/A rev.00

Issue date:

2023-05-17

Final address:

**PHILADELPHIA SOLAR
Alqastel Industrial Area, Ammam, Jordan**

Testing sample:

**(Photovoltaic Modules)
PS-M144(HCBF)-540 W**

Test type:

Extreme hail test

Test result:

PASS

Reference Standard:

**IEC 61215-1:2021 / EN 61215-1: 2021
IEC 61215-2: 2021 / EN 61215-2: 2021
IEC 61215-1-1: 2021 / EN 61215-1-1: 2021
PTG 60 1.01 Electroluminescence test**

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Test Report IEC 61215-1:2021/ EN 61215-1:2021 Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Part 1: Test requirements IEC 61215-2:2021 / EN 61215-2:2021 Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Part 2: Test procedures IEC 61215-1-1:2021/ EN 61215-1-1:2021 Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Special requirements for testing of crystalline silicon photovoltaic (PV) modules PTG 60 1.01 Elettroluminescenza	
Test Report Approved by Tested by Issued date	Maurizio Lorenzon - <i>Head of the Lab</i> Andrea Cupido Sergio Merighi 2023-05-17
Test laboratory Name Address	Kiwa Cermet Italia S.p.A Via Fabio Filzi 68, 20032 Cormano (MI)
Final Addressee Name Address Contact person	Philadelphia Solar Alqastel Industrial Area, Ammam, Jordan Ms. Marwa Ghaith
Test details Reference standard Requested	IEC 61215-2:2021 – IEC 61215-1-1 – IEC 61730-2 <u>IEC 61215-2 – IEC 61215-1-1</u> MQT 01 Visual inspection MQT 02 Maximum power determination MQT 03 Insulation test → N/A ¹ MQT 04 Measurement of temperature coefficients → N/A ¹ MQT 05 Measurement of nominal module operating temperature → N/A ¹ MQT 06.1 Performance at STC → N/A ¹ MQT 06.2 Performance at NMOT → N/A ¹ MQT 07 Performance at low irradiance → N/A ¹ MQT 08 Outdoor exposure test → N/A ¹ MQT 09 Hot-spot endurance test → N/A ¹ MQT 10 UV preconditioning test → N/A ¹ MQT 11 Thermal cycling test → N/A ¹ MQT 12 Humidity-freeze test → N/A ¹ MQT 13 Damp heat test → N/A ¹

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MQT 14 Robustness of terminations → N/A¹
MQT 15 Wet leakage current test
MQT 16 Static mechanical load test → N/A¹
MQT 17 Hail test
MQT 18 Bypass diode testing → N/A¹
MQT 19.1 Initial stabilization → N/A¹
MQT 19.2 Final stabilization → N/A²
IEC 61730-2
MST 01 Visual inspection → N/A¹
MST 02 Performance at STC → N/A¹
MST 03 Maximum power determination → N/A¹
MST 04 Insulation thickness test → N/A¹
MST 05 Durability of markings → N/A¹
MST 06 Sharp edge test → N/A¹
MST 07 Bypass diode functionality test → N/A¹
MST 11 Accessibility test → N/A¹
MST 12 Cut susceptibility test → N/A¹
MST 13 Continuity test of equipotential bonding → N/A²
MST 14 Impulse voltage test → N/A¹
MST 16 Insulation test → N/A¹
MST 17 Wet leakage current test → N/A¹
MST 21 Temperature test → N/A¹
MST 22 Hot-spot endurance test → N/A¹
MST 23 Fire Test → N/A¹
MST 24 Ignitability test → N/A¹
MST 25 Bypass diode thermal test → N/A¹
MST 26 Reverse current overload test → N/A¹
MST 32 Module breakage test → N/A¹
MST 33 Screw connections test → N/A¹
MST 34 Static mechanical load test → N/A¹
MST 35 Peel test → N/A¹
MST 36 Lap shear strength test → N/A¹
MST 37 Materials creep test → N/A¹
MST 42 Robustness of terminations test → N/A¹
MST 51 Thermal cycling test → N/A¹
MST 52 Humidity freeze test → N/A¹
MST 53 Damp heat test → N/A¹
MST 54 UV test → N/A¹
MST 55 Cold conditioning → N/A¹
MST 56 Dry heat conditioning → N/A¹
INTERNAL METHOD
1.01 Electroluminescence test


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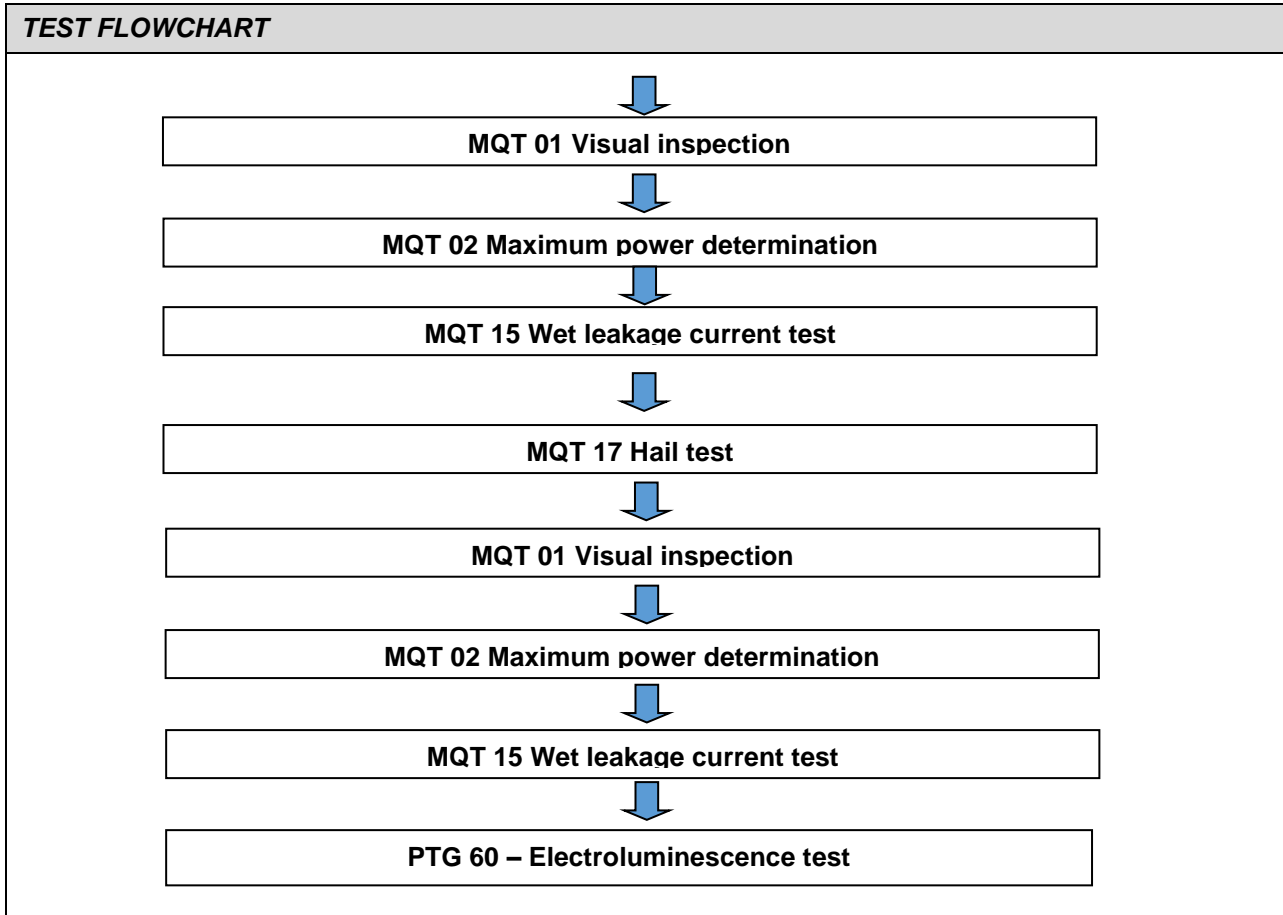
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Sample details	Photovoltaic Modules (PV)
Brand	 Philadelphia Solar <small>DELIVERING CLEAN ENERGY SOLUTIONS</small>
Manufacturer	PHILADELPHIA SOLAR
Model/reference type	PS-M144(HCBF) – 540 W
Remarks	N/A ¹ → Not required by the customer

TESTS	
<p>List of Performed Test (Test name)</p> <p><u>IEC 61215-2 - IEC 61215-1-1</u></p> <p>MQT 01 Visual inspection ¹</p> <p>MQT 02 Maximum power determination</p> <p>MQT 15 Wet leakage current test ¹</p> <p>MQT 17 Hail test</p> <p><u>INTERNAL METHOD</u></p> <p>1.01 Electroluminescence test</p>	<p>Test site</p> <p>Kiwa Cermet Italia S.p.A</p> <p>Via Fabio Filzi 68, 20032 Cormano (MI)</p>
<p>Remarks: ¹ The Declarations of Conformity the expanded measurement uncertainty is not taken into account, therefore, in the case of values approaching the acceptability limits, we consider a level of risk of up to 50% of erroneous acceptance (if the value coincides with the limit, the risk level is equal to 50%). Similarly, in the case of a value exceeding the acceptability limit, the risk level of erroneous rejection can be up to 50%.</p>	

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TECHNICAL SPECIFICATIONS OF THE SAMPLE UNDER TEST	
General features	
Model designation	PS-M144(HCBF) – 540 W
Module dimensions (length x width x height) (mm)	2277x1133x35
Module weight (kg)	Not declared
Cell	
Cell dimensions (length x width) (mm)	182x182
Cell thickness (mm)	175 ± 17.5
Cell technology	Mono-crystalline, Bifacial Solar Cells
Cell manufacturer	United Renewable Energy
Cell model type / part number	Black22 Series
Number of bus bars	10
Total number of cells	144 Half Cell (72 full cell)
Number of cells in series	
Number of cells in parallel	
Number of cells for each diode	48 half cell
Electrical circuit (S, SP, PS)	72 in series/ 2 in parallel
Diode	
Number of bypass diodes	3
Diode manufacturer	JMTHY
Diode model type / part number	MK5050
Bypass diode rated current (A)	50
Bypass diode max junction temperature (°C)	200
Cell connectors and string connectors (PV ribbon)	
Cell connectors manufacturer	TaiCang Juren
Cell connectors material (please declare the metallic percentage, e.g. Sn60Pb40)	Sn60Pb40
Cell connectors dimensions (width x thickness) (mm x mm)	Round 0.35 -0.005/+0.015 mm
String connectors manufacturer	TaiCang Juren
String interconnect material (please declare the metallic percentage, e.g. Sn60Pb40)	Sn60Pb40
String connectors dimensions (width x thickness) (mm x mm)	5 x 0.4
Soldering material	Sn60Pb40
Fluxing agent	Kester 952-S
Superstrate (front cover)	
Superstrate manufacturer	Xinyi PV Products (Anhui) Holdings. Ltd.
Superstrate material	AR coated, Tempered Glass
Superstrate model type / part number	3.2-mm thick
Superstrate thickness (mm)	3.2
Substrate (rear cover)	
Substrate manufacturer	Cybrid
Substrate material	Transparent- kpf
Substrate model type / part number	Cynagard 465A(R)
Substrate thickness (mm)	0.320
Encapsulant	
Encapsulant manufacturer (front side)	SVECK
Encapsulant material (front side)	EVA
Encapsulant model type / part number (front side)	SV-15296P
Encapsulant manufacturer (back side)	SVECK
Encapsulant material (back side)	EVA

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Encapsulant model type / part number (back side)	SV-15297P
Junction box, cables and connectors	
Junction box manufacturer	JMTHY
Junction box model type / part number	JM37xy
Junction box potting material (if any)	Shanghai Huitian New Material Co.
Junction box adhesive manufacturer	Shanghai Huitian New Material Co.
Junction box adhesive material	RTV Sealant
Junction box adhesive model type / part number	HT906Z
Cable type	H1Z2Z2-K
Cable manufacturer	JMTHY
Connector type/model	PV-JM608
Connector manufacturer	JMTHY
Insulation tape	
Insulation tape manufacturer	N/A
Insulation tape material	N/A
Cell fixing tape	
Cell fixing material manufacturer	Cybrid Technologies
Cell fixing material	FF-3665
Label	
Nameplate label manufacturer	SUZHOU ZhengAo Packing Material CO., LTD
Nameplate label material	polymers
Nameplate label adhesive	N/A
Barcode ID material	N/A
Barcode ID adhesive	N/A
PV electrical and mechanical data	
Maximum system voltage [V]	1500
Open-circuit voltage, Voc [V]	49.8
Voc tolerance [%]	± 5
Short-circuit current, Isc [A]	13.62
ISC tolerance [%]	± 5
Maximum power voltage, Vmp [V]	41.70
Maximum power current, Imp [A]	12.95
Maximum power, Pmp [W]	540
Power tolerance [%]	± 3
Maximum overcurrent protection rating [A]	25
Safety factor γ_m	1.5
Design Load Positive [Pa] (Snow)	3600
Design Load Negative [Pa] (Wind)	1600
Hail test - Ice ball diameter (mm)	45
Material group	N/A
Pollution Degree (PD) according to IEC 60664-1	1
Rated operating altitude (m)	2000
Remarks: The data in this table were provided by the customer If the information provided by the customer can affect the validity of the results, the laboratory declines any responsibility	

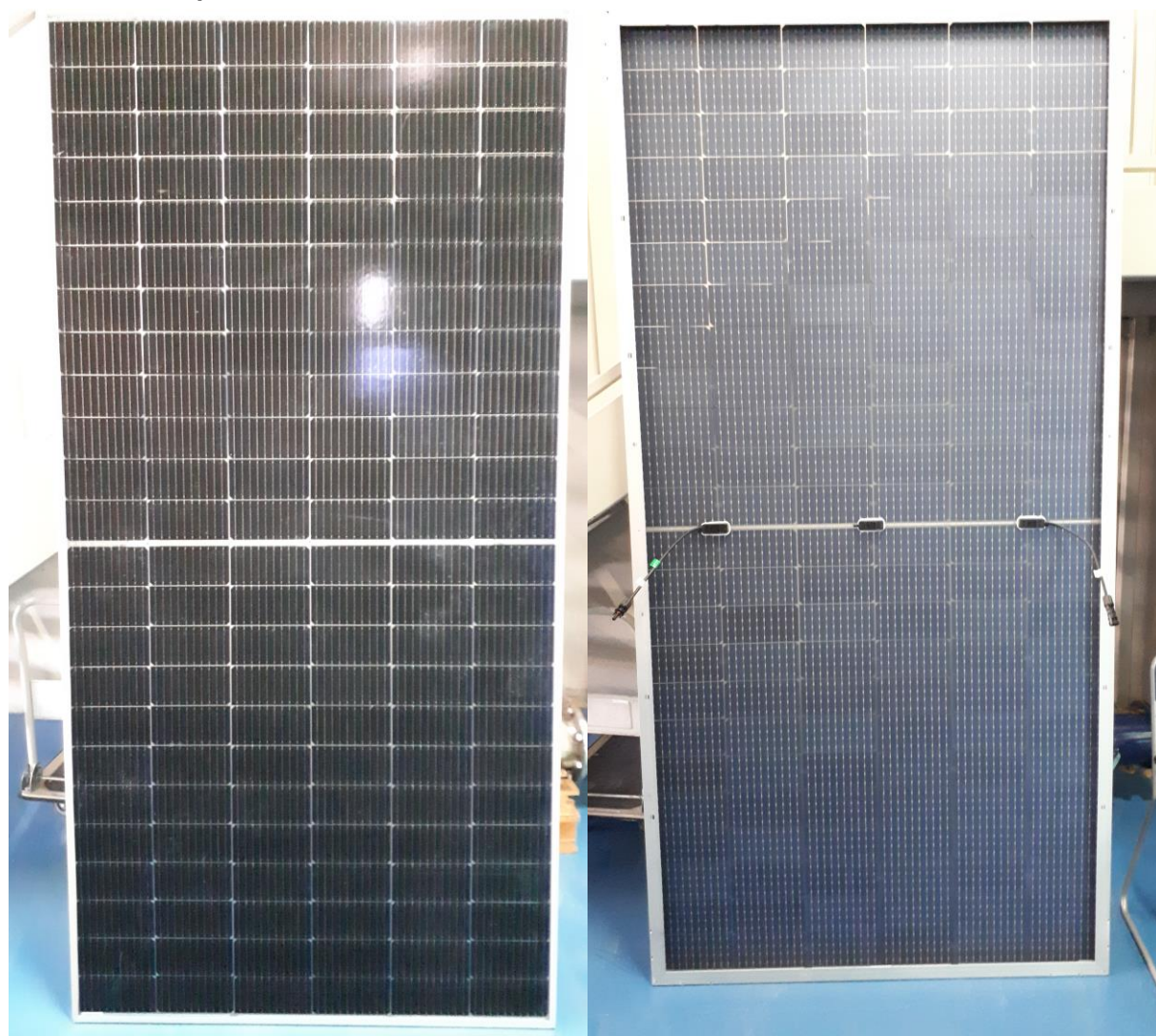
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Nameplate marking:



Pictures of samples: front and back side



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Test result Abbreviation:	
Not applicable	N/A
The sample is conformed to the requirements	P (Pass)
The sample is not conformed to the requirements	F (Fail)
Dates	
Receipt date of testing samples	2022/11/02
Test date	2023/04/28
Abbreviations and Symbols	
Pmp – Maximum power	HF – Humidity Freeze
Vmp – Maximum power voltage	DH – Damp Heat
Imp – Maximum power current	TC – Thermal Cycling
Isc – Short circuit current	α – Current temperature coefficient
Voc – Open circuit voltage	β – Voltage temperature coefficient
FF – Fill factor	δ – Power temperature coefficient
Eff – Cell efficiency	NMOT – Nominal Module Operating Temperature
STC – Standard Test Conditions	VFM _{rated} – Rated diode(s) forward voltage
MQT – Module Quality Tests	NP – Nameplate
MST – Module Safety Tests	m ₂ – The measurement uncertainty in % of laboratory for Voc
VFM – Measured diode(s) forward voltage	t ₁ – The manufacturer's rated lower production tolerance in % for Pmp
m ₁ – The measurement uncertainty in % of laboratory for Pmp	t ₃ – The manufacturer's rated upper production tolerance in % for Isc
m ₃ – The measurement uncertainty in % of laboratory for Isc	@ – At value of
t ₂ – The manufacturer's rated upper production tolerance in % for Voc	
r – Pmp measurement reproducibility	
Remarks	
The test results shown in this test report are exclusively referred to the tested samples. The results refer to the sample as received. This test report cannot be reproduced in part without a written permission of KIWA S.p.a "(Cf. annex #)" it refers to other information annexed to the report. "(see annexed table)" it refers to a table annexed to the report.	

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GENERAL PRODUCT INFORMATION AND OTHER REMARKS:

- New module type
- Modifications (if yes, please choose the applicable modification according to the IEC TS 62915):
- Original test report ref. No:
- Modification according to the IEC TS 62915:
 - Test programs for crystalline silicon PV modules
 - 4.2.1 Modification to frontsheet
 - 4.2.2 Modification to encapsulation system
 - 4.2.3 Modification to cell technology
 - 4.2.4 Modification to cell and string interconnect material or technique
 - 4.2.5 Modification to backsheet
 - 4.2.6 Modification to electrical termination
 - 4.2.7 Modification to bypass diode
 - 4.2.8 Modification to electrical circuitry
 - 4.2.9 Modification to edge sealing
 - 4.2.10 Modification to frame and/or mounting structure
 - 4.2.11 Change in PV module size
 - 4.2.12 Higher or lower output power (by 10 % or more) with the identical design and size and using the identical cell process
 - 4.2.13 Increase of over-current protection rating
 - 4.2.14 Increase of system voltage
 - 4.2.15 Change in cell fixing tape
 - Test programs for thin-film PV modules
 - 4.3.1 Modification to frontsheet
 - 4.3.2 Modification to encapsulation system
 - 4.3.3 Modification to front contact (e. g. TCO)
 - 4.3.4 Modification to cell technology
 - 4.3.5 Modification to cell layout
 - 4.3.6 Modification to back contact
 - 4.3.7 Modification to edge deletion
 - 4.3.8 Modification to interconnect material or technique
 - 4.3.9 Modification to backsheet
 - 4.3.10 Modification to electrical termination
 - 4.3.11 Modification to bypass diode
 - 4.3.12 Modification to edge sealing
 - 4.3.13 Modification to frame and/or mounting structure
 - 4.3.14 Change in PV module size
 - 4.3.15 Higher or lower output power (by 10 % or more) with the identical design and size
 - 4.3.16 Increase of over-current protection rating
 - 4.3.17 Increase of system voltage
- Other: **extreme hail test according to the table "TEST FLOWCHART".**

Remarks: /

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TABLE 1	SAMPLING	
	Sampling is made under the responsibility of the customer	
	The customer has selected 1 sample	
	The tested PV modules/samples has been sent by the customer	


TABLE 2	MARKING	
	Name, monogram or symbol of manufacturer:	 Philadelphia Solar DELIVERING CLEAN ENERGY SOLUTIONS
	Type or model number:	PS-M144(HCBF)- 540 W
	Serial number of the tested samples	PS091022B144014017
	Maximum system voltage:	1500 V
	Production site:	PHILADELPHIA SOLAR Alqastel Industrial Area, Ammam, Jordan
<i>Supplementary information: /</i>		

TABLE 3	TEST PROCEDURES	
IEC 61215-2		
MQT 01	Visual inspection	Table 4.1
MQT 02	Maximum power determination	Table 4.2
MQT 15	Wet leakage current test	Table 4.15
MQT 17	Hail test	Table 4.17
INTERNAL METHOD		
1.01	Electroluminescence	Table 1.01

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TABLE 4	IEC 61215-1: MAJOR VISUAL DEFECTS	
	a) Broken, cracked, or torn external surfaces.	Table 10.2
	b) Bent or misaligned external surfaces, including superstrates, substrates, frames and junction boxes to the extent that the operation of the PV module would be impaired.	Table 10.2
	c) Bubbles or delaminations forming a continuous path between electric circuit and the edge of the module.	Table 10.2
	d) If the mechanical integrity depends on lamination or other means of adhesion, the sum of the area of all bubbles shall not exceed 1 % of the total module area.	Table 10.2
	e) Evidence of any molten or burned encapsulant, backsheets, frontsheet, diode or active PV component.	Table 10.2
	f) Loss of mechanical integrity to the extent that the installation and operation of the module would be impaired.	Table 10.2
	g) Cracked/broken cells which can remove more than 10 % of the cell's photovoltaic active area from the electrical circuit of the PV module.	Table 10.2
	h) Voids in, or visible corrosion of any of the layers of the active (live) circuitry of the module extending over more than 10 % of any cell.	Table 10.2
	i) Broken interconnections, joints or terminals.	Table 10.2
	j) Any short-circuited live parts or exposed live electrical parts.	Table 10.2
	k) Module markings (label) are no longer attached or the information is unreadable.	Table 10.2

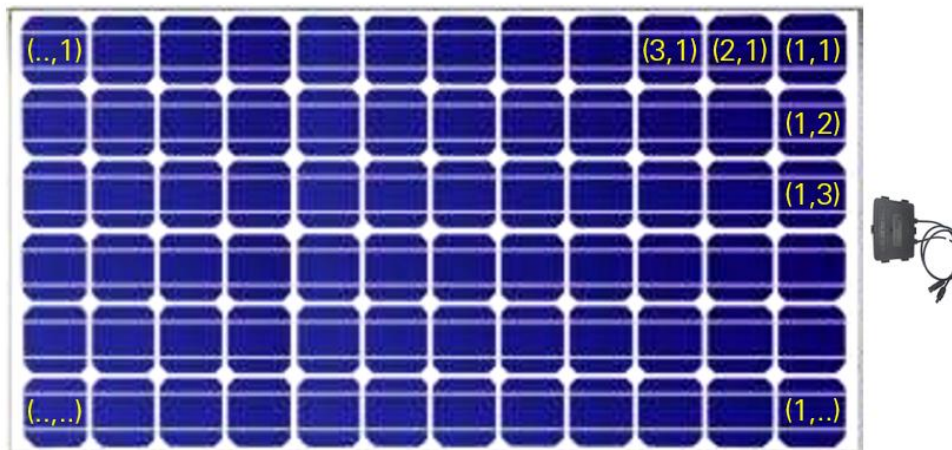


Figure 4 - Cells identification number

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TABLE 5		
Measured parameter	Expanded Uncertainty	Unit
Test 4.1 - Visual Inspection MQT 01		
Length (Caliper)	0.5	mm
Length (Tape)	2	mm
Test 4.2 - Maximum power determination MQT 02		
V_{oc}	0.3	%
I_{sc}	2.5	%
P_{mp}	3	%
Irradiance	21	Wm^{-2}
Temperature	0.7	°C
Test 4.15 - Wet leakage current test MQT 15		
Electrical Insulation (surface > 0.1 m ²)	25	% ¹
Voltage	1	%
Humidity	3	%RH
Resistivity	165	Ωcm
Temperature	0.6	°C
¹ Percentage on the reading value given in $M\Omega m^2$		
Test 4.17 - Hail test MQT 17		
Hail speed	0.7	m/s
Hail diameter	0.46 (@25 mm)	mm
Hail weight	0.1 (@25 mm)	g
Hail diameter	1.26 (@45 mm)	mm
Hail weight	0.8 (@45 mm)	g
Hail diameter	0.86 (@55 mm)	mm
Hail weight	0.7 (@55 mm)	g
Remarks		
Test 1.01 - Electroluminescence test		
Current	0.01	A
Voltage	0.01	V
Time	0.4	s
Remarks		
The measurement uncertainties stated in this document have been determined according to EA-4/02. Usually, they have been estimated as expanded uncertainty obtained multiplying the standard uncertainty by the coverage factor $k = 2$ corresponding to a confidence level of about 95%.		


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 **IEC 61215-1-1**

IEC 61215-1-1:2016 Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Special requirements for testing of crystalline silicon photovoltaic (PV) modules			
5	Marking and documentation	This test of IEC 61215-1:2021 is applicable without modifications.	—
6	Testing	This test of IEC 61215-1:2021 is applicable without modifications.	—
7	Pass criteria	This test of IEC 61215-1:2021 is applicable without modifications. The maximum allowable value of reproducibility is set to $r = 1,0 \%$. The maximum allowable value of measurement uncertainty is set to $m_1 = 3,0 \%$.	—
8	Major visual defects	This test of IEC 61215-1:2021 is applicable without modifications.	—
9	Report	This test of IEC 61215-1:2021 is applicable without modifications.	—
10	Modifications	This test of IEC 61215-1:2021 is applicable without modifications.	—
11	Test flow and procedures	This test of IEC 61215-1:2021 is applicable without modifications.	—
11.1	Visual inspection (MQT 01)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.2	Maximum power determination (MQT 02)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.3	Insulation test (MQT 03)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.4	Measurement of temperature coefficients (MQT 04)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.5	Measurement of nominal module operating temperature (NMOT) (MQT 05)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.6	Performance at STC (MQT 06.1) and NMOT (MQT 06.2)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.7	Performance at low irradiance (MQT 07)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.8	Outdoor exposure test (MQT 08)	This test of IEC 61215-2:2021 is applicable without modifications.	—

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11.9	Hot-spot endurance test (MQT 09)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.10	UV preconditioning test (MQT 10)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.11	Thermal cycling test (MQT 11)	This test of IEC 61215-2:2021 is applicable without modifications. For monofacial modules the applied current shall be equal to the STC peak power current. For bifacial modules the applied current shall be to the peak power current at the elevated irradiance level BSI.	—
11.12	Humidity-freeze test (MQT 12)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.13	Damp heat test (MQT 13)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.14	Robustness of terminations test (MQT 14)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.15	Wet leakage current test (MQT 15)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.16	Static mechanical load test (MQT 16)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.17	Hail test (MQT 17)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.18	Bypass diode thermal test (MQT 18)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.19	Stabilization (MQT 19)	This test of IEC 61215-2:2021 is applicable without modifications. For the definition of stabilization as per test MQT 19 of IEC 61215-2:2021, $x = 0,01$ shall be used for crystalline silicon PV modules.	—
11.20	Cyclic (dynamic) mechanical load test (MQT 20)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.21	Potential induced degradation test (MQT 21)	This test of IEC 61215-2:2021 is applicable without modifications.	—
11.22	Bending test (MQT 22)	This test of IEC 61215-2:2021 is applicable without modifications.	—

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IEC 61215-2 – IEC 61215-1-1

Test 4.1		TABLE 4.1: Visual Inspection MQT 01			
Initial Examination					
Sample serial number	Test Date	Nature and position of initial finding - description		P/F	
PS091022B144014017	2023/04/28	No major visual defects		P	
Final examinations					
IEC 61215					
After the 4.17 Hail test MQT 17					
PS091022B144014017	2023/04/28	No major visual defects		P	
<i>Supplementary information:</i> The requirements of the final visual inspection are listed in the Table 4. For identification of cell number see figure 4. <i>Remarks:</i> /					

Test 4.2		TABLE 4.2: Maximum power determination MQT 02								
Initial measurements										
Temperature (°C)						25				
Irradiance (W/m ²)						1000				
Light Source Spectrum						AM1.5				
Sample serial number	Test date	Temp (°C)	Voc (V)	Vmp (V)	Isc (A)	Imp (A)	Pmp (W)	Eff (%)	FF (%)	
PS091022B144014017	2023/04/28	25.0	49.66	42.05	13.51	12.89	542.2	21.1	80.8	
Final measurements										
Temperature (°C)						25				
Irradiance (W/m ²)						1000				
Light Source Spectrum						AM1.5				
Sample serial number	Test date	Temp (°C)	Voc (V)	Vmp (V)	Isc (A)	Imp (A)	Pmp (W)	Eff (%)	FF (%)	
PS091022B144014017	2023/04/28	25.0	49.63	42.07	13.35	12.77	537.3	20.9	81.1	
<i>Supplementary information:</i> /										

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Test 4.15		TABLE 4.15: Wet leakage current test MQT 15							
Admissible resistivity of the water solution ($\Omega \cdot \text{cm}$)				< 3500					
Admissible temperature of the water solution ($^{\circ}\text{C}$)				22 ± 2					
DC Voltage (V)				1500					
Module Area (m^2)				2.579					
Sample serial number	Test date	Resistivity of the water solution ($\Omega \cdot \text{cm}$)	Water solution temperature ($^{\circ}\text{C}$)	Environment		Applied Voltage (V)	$\text{M}\Omega \cdot \text{m}^2$ @ Applied Voltage	P/F	
				Temp. ($^{\circ}\text{C}$)	Humidity (%R.H.)				
Initial values									
PS091022B144014017	2023/04/28	1097	22.8	25.1	38	1584	19088	P	
Final values									
IEC 61215									
After the 4.17 Hail test MQT 17									
PS091022B144014017	2023/04/28	1097	22.8	25.1	38	1585	18620	P	
<u>Supplementary information:</u> /									
<u>Remarks:</u> Test has been passed (P) if:									
– For modules with an area of less than $0,1 \text{ m}^2$ the insulation resistance shall not be less than $400 \text{ M}\Omega$.									
– For modules with an area larger than $0,1 \text{ m}^2$ the measured insulation resistance times the area of the module shall not be less than $40 \text{ M}\Omega \cdot \text{m}^2$.									

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LAB N° 0001 L

Test 4.17		TABLE 4.17: Hail test MQT17	
Test date		2023/04/28	
Sample serial number		PS091022B144014017	
Spheres reference diameter (mm)		45 ± 5%	
Spheres reference weight (g)		43.9 ± 5%	
Spheres reference speed (m/sec)		30.7 ± 5%	
SHOT NO.	VELOCITY (m/s)		P/F
N. 1	30.2		P
N. 2	30.9		P
N. 3	29.9		P
N. 4	29.5		P
N. 5	30.2		P
N. 6	29.7		P
N. 7	29.3		P
N. 8	29.2		P
N. 9	29.5		P
N. 10	30.6		P
N. 11	29.3		P
Control tests			
4.1 Visual Inspection MQT 01 (P/F)		4.15 Wet leakage current test MQT 15 (P/F)	
P		P	

Supplementary information:

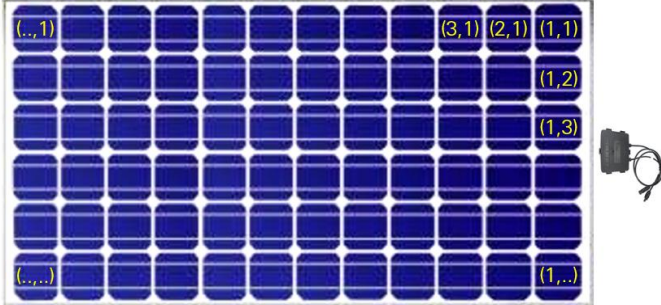
Shot No.	Location
1	Any corner of the module window, not more than one radius from the module edge.
2	Any edge of the module, not more than one radius of ice-ball from the module edge.
3, 4	Over edges of the circuit (e.g. individual cells).
5, 6	Over the circuit near interconnects (i.e. cell interconnects and bus ribbons).
7, 8	On the module window, not more than half diameter of ice ball from one of the points at which the module is mounted to the supporting structure.
9, 10	On the module window, at points farthest from the points selected above.
11	Any points which may prove especially vulnerable to hail impact like over the junction box.

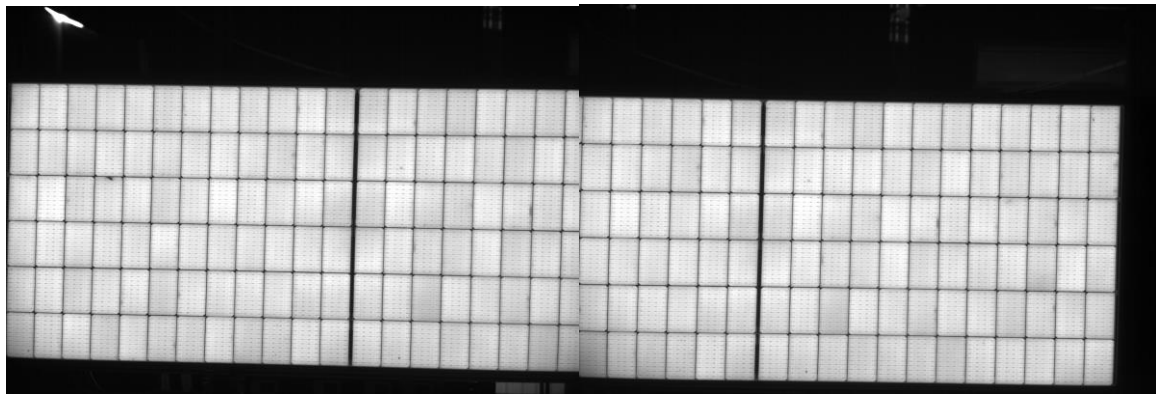
Remarks: The module passes (P) the test if:

- No evidence of major visual defects, as defined in Table 4 (Table 4.1);
- Wet leakage current shall meet the same requirements as for the initial measurements (Table 4.15).

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Test 1.01	TABLE 1.01: Electroluminescence test					
Sample serial number	Test date	Environmental Temperature (°C)	Exposure time (s)	Reverse current (A)	Supply Voltage (V)	ISC (A)
Initial examination						
PS091022B144014017	2023/05/16	25.2	5	12.95	54.04	13.62
<i>Supplementary information:</i> The Electroluminescence test is a qualitative test, its result cannot be PASS or FAIL.						
<i>Cells identification number:</i>						
						



1. Micro cracks for example on cells (3;23)

Figure 1.01.1 – Sample n. PS091022B144014017 Electroluminescence test

----- End of the Test Report n. L0012337/A rev.00-----